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Examiner Signature

Sheet 1 of 2

IAU	Complete if Known		
Application Number	10/003,331		
Filing Date	October 31, 2001		
First Named Inventor	Slater		
Group Art Unit			
Examiner Name			
Attorney Docket Number	5000 113A		

U.S. PATENT DOCUMENTS							
Examiner	Cite No.1	U.S. Patent Docu Number Kind C (if kno	Code ²	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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	Examiner Initials*	Cite Time	Fore Office ³		ment (ind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T _e
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	DV	10	JP	09082663		Fuji Electric Co. Ltd.	03-28-1997		
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the

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Substitute	for form 1449A/PTC	, , , , ,	Complete if Known		
	DIATION	DIGGL GOLIDE	Application Number	10/003,331	
INFORMATION DISCLOSURE			Filing Date	October 31, 2001	
STATEMENT BY APPLICANT		First Named Inventor	Slater		
			Group Art Unit		
	(use as many she	ets as necessary)	Examiner Name		
Sheet	2	of 2	Attorney Docket Number	5000.113A	

	ASPACE.	OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T 2
bV _	1 2 Table 1 2 Table 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	SPIEß (aka "Spiess"), Aluminum implantation of p-SiC for ohmic contacts, First European Conference on Silicon Carbide and Related Materials (ECSCRM 96), Oct. 6-9, 1996, pp. 1414-1419, Vol. 6; no. 10, Elsevier, Switzerland	
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